# FAIRCHILD SEMICONDUCTORIM

**PRELIMINARY** 

July 1998

# FM27C040 4,194,304-Bit (512K x 8) High Speed CMOS EPROM

# **General Description**

The FM27C040 is a high performance, 4,194,304-bit Electrically Programmable Read Only Memory. It is organized as 512K words of 8 bits each. Its pin-compatibility with byte-wide JEDEC EPROMs enables upgrades through 8 Mbit EPROMs. The "Don't Care" feature on V<sub>PP</sub> during read operations allows memory expansions from 1M to 4Mbits with no printed circuit board changes.

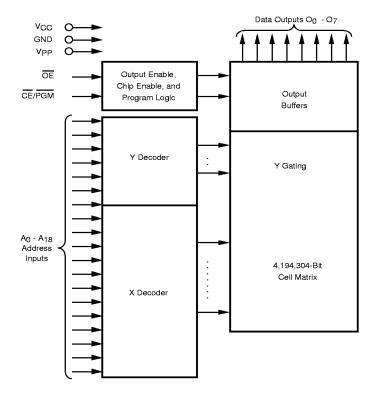
The FM27C040 provides microprocessor-based systems extensive storage capacity for large portions of operating system and application software. Its 45ns access time provides high speed operation with high-performance CPUs. The FM27C040 offers a single chip solution for the code storage requirements of 100% firmware-based equipment. Frequently used software routines are quickly executed from EPROM storage, greatly enhancing system utility.

The FM27C040 is manufactured using Fairchild's advanced CMOS  $AMG^{TM}$  EPROM technology.

# **Features**

- High performance CMOS —45, 55, 70ns access time
- Simplified upgrade path
  - -V<sub>PP</sub> is a "Don't Care" during normal read operation
- Manufacturer's identification code
- JEDEC standard pin configuration
  - —32-pin PDIP
  - -32-pin PLCC
  - -32-pin TSOP

# **Block Diagram**



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# **Connection Diagrams**

27C080	27C020	27C010	FM27	C040	27C010	27C020	27C080
A <sub>19</sub>	XX/V <sub>PP</sub>	XX/V <sub>PP</sub>	XX/V <sub>PP</sub> 1	32 □ V <sub>CC</sub>	V <sub>C</sub> C	Vcc	Vcc
A16	A16	A16	A16 🗆 2	31 A18	XX/PGM	XX/PGM	A18
A15	A15	A <sub>15</sub>	A <sub>15</sub> 🗆 3	30 🗀 A17	NC	A17	A17
A12	A12	A12	A12 4	29 🗀 A14	A14	A14	A14
A7	A7	A7	A7 🗆 5	28 🗀 A13	A13	A13	A13
A <sub>6</sub>	A <sub>6</sub>	A <sub>6</sub>	A6 🗆 6	27 🗀 A8	A8	A8	A8
A5	A5	A5	<b>A</b> 5 □ 7	26 🗀 A9	A9	A9	A9
A <sub>4</sub>	A <sub>4</sub>	A <sub>4</sub>	A4 🗌 8	25 🗀 A11	A11	A11	A11
A3	А3	А3	Аз 🗆 9	24 🗆 ŌĒ	ŌĒ	ŌĒ	OE/Vpp
A <sub>2</sub>	A <sub>2</sub>	A <sub>2</sub>	A <sub>2</sub> 🗆 10	23 🗀 A10	A10	A10	A10
A <sub>1</sub>	A <sub>1</sub>	A <sub>1</sub>	A1 🗆 11	22 CE/PGM	CE	CE	CE/PGM
A <sub>0</sub>	A <sub>0</sub>	A <sub>0</sub>	A <sub>0</sub> 🗆 12	21 🗀 07	07	07	07
00	00	00	O <sub>0</sub> 🗌 13	20 D O6	06	06	06
01	01	01	O1 🗌 14	19 🗀 O5	05	05	05
02	02	02	O2 🗌 15	18 🗀 O4	04	04	04
GND	GND	GND	GND ☐ 16	17 O3	О3	О3	О3

Note: Compatible EPROM pin configurations are shown in the blocks adjacent to the FM27C040 pin.

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# Commercial Temperature Range (0°C to +70°C) $V_{CC}$ = 5V $\pm$ 10%

Parameter/Order Number	Access Time (ns)
FM27C040 N, T, V 45	45
FM27C040 N, T, V 55	55
FM27C040 N, T, V 70	70

# **Pin Names**

A0-A18	Addresses
CE/PGM	Chip Enable/Program
ŌĒ	Output Enable
00–07	Outputs
XX	Don't Care (During Read)

# Extended Temperature Range (-40°C to +85°C) $V_{CC} = 5V \pm 10\%$

Parameter/Order Number	Access Time (ns)			
FM27C040 NE, TE, VE 55	55			
FM27C040 NE, TE, VE 70	70			

Package Types: FM27C040 N,T, V XXX

N = Plastic DIP

T = TSOP

V = PLCC

- All packages conform to the JEDEC standard.
- All versions are guaranteed to function for slower speeds.

# **Absolute Maximum Ratings** (Note 1)

Storage Temperature -65°C to +150°C

All Input Voltages except A9 with

Respect to Ground -0.6V to +7V

V<sub>PP</sub> and A9 with Respect to Ground -0.6V to +14V

V<sub>CC</sub> Supply Voltage with

Respect to Ground -0.6V to +7V

ESD Protection >2000V

All Output Voltages with Respect to Ground

 $V_{\rm CC}$  +1.0V to GND - 0.6V

# **Operating Range**

Range	Temperature	V <sub>cc</sub>	Tolerance		
Commercial	0°C to +70°C	+5V	±10%		
Industrial	-40°C to +85°C	+5V	±10%		

# **Read Operation**

# **DC Electrical Characteristics** Over operating range with $V_{PP} = V_{CC}$

Symbol	Parameter	Test Condit	tions	Min	Max	Units
V <sub>IL</sub>	Input Low Level			-0.5	0.8	V
V <sub>IH</sub>	Input High Level			2.0	V <sub>CC</sub> +0.5	V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA			0.45	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -2.5 mA		2.4		V
I <sub>SB1</sub>	V <sub>CC</sub> Standby Current (CMOS)	$\overline{\text{CE}} = V_{\text{CC}} \pm 0.3V$			100	μΑ
I <sub>SB2</sub>	V <sub>CC</sub> Standby Current	CE = V <sub>IH</sub>			1	mA
I <sub>CC</sub>	V <sub>CC</sub> Active Current	CE = OE = V <sub>IL</sub> , I/O = 0 mA	'E'		25	mA
I <sub>PP</sub>	V <sub>PP</sub> Supply Current	$V_{PP} = V_{CC}$			10	μА
V <sub>PP</sub>	V <sub>PP</sub> Read Voltage			V <sub>CC</sub> - 0.4	V <sub>cc</sub>	V
ILI	Input Load Current	V <sub>IN</sub> = 5.5V or GND		-1	1	μΑ
I <sub>LO</sub>	Output Leakage Current	V <sub>OUT</sub> = 5.5V or GNE	)	-10	10	μА

# AC Electrical Characteristics Over operating range with $V_{PP} = V_{CC}$

Symbol	Parameter	45		55		70		Units	
		Min	Max	Min	Max	Min	Max		
t <sub>ACC</sub>	Address to Output Delay		45		55		70		
t <sub>CE</sub>	CE to Output Delay		45		55		70		
t <sub>OE</sub>	OE to Output Delay		20		25		30	1	
t <sub>DF</sub> (Note 2)	Output Disable to Output Float		20		25		30	ns	
t <sub>OH</sub> (Note 2)	Output Hold from Addresses CE or OE , Whichever Occurred First	0		0		0			

# **Capacitance** $T_A = +25^{\circ}C$ , f = 1 MHz (Note 2)

Symbol	Parameter	rameter Conditions		Max	Units	
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0V	9	15	pF	
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	12	15	pF	
C <sub>VPP</sub>	V <sub>PP</sub> Capacitance	$V_{PP} = 0V$	18	25	pF	

# **AC Test Conditions**

# **Test Load**

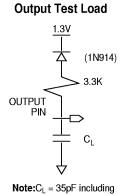
Output Load  $C_L$  = 35 pF and R = 121 $\Omega$ 

Input Rise and Fall Times ≤5 ns

Input Pulse Levels 0V to 3.0V

Timing Measurement Reference Level (Note 9)

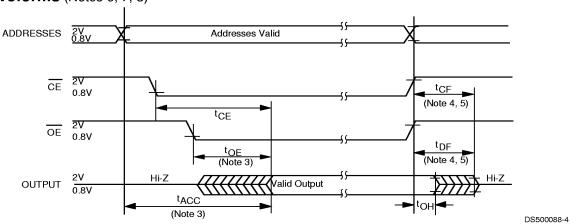
1.5V Inputs Outputs` 1.5V



jig capacitance

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# AC Waveforms (Notes 6, 7, 8)



Note 1: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note 2: This parameter is only sampled and is not 100% tested.

 $\textbf{Note 3:} \ \ \overline{\text{OE}} \ \text{may be delayed up to } t_{\text{ACC}} \text{--} t_{\text{OE}} \text{ after the falling edge of } \overline{\text{CE}} \text{ without impacting } t_{\text{ACC}}.$ 

**Note 4:** The  $t_{DF}$  and  $t_{CF}$  compare level is determined as follows: High to TRI-STATE®, the measured  $V_{OH1}$  (DC) - 0.10V; Low to TRI-STATE, the measured  $V_{OL1}$  (DC) + 0.10V.

Note 5: TRI-STATE may be attained using  $\overline{\text{OE}}$  or  $\overline{\text{CE}}$ 

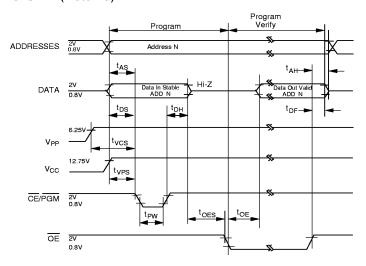
Note 6: The power switching characteristics of EPROMs require careful device decoupling. It is recommended that at least a 0.1 µF ceramic capacitor be used on every device between V<sub>CC</sub> and GND.

Note 7: The outputs must be restricted to  $V_{CC}$  + 1.0V to avoid latch-up and device damage.

Note 8:  $V_{PP}$  may be connected to  $V_{CC}$  except during programming.

Note 9: Inputs and outputs can undershoot to -2.0V for 20 ns Max.

# **Programming Waveform** (Note 13)



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# **Programming Characteristics** (Notes 10, 11, 12, 13)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
t <sub>AS</sub>	Address Setup Time		1			μs
t <sub>OES</sub>	OE Setup Time		1			μs
t <sub>DS</sub>	Data Setup Time		1			μs
t <sub>VPS</sub>	V <sub>PP</sub> Setup Time		1			μs
t <sub>vcs</sub>	V <sub>CC</sub> Setup Time		1			μs
t <sub>AH</sub>	Address Hold Time		0			μs
t <sub>DH</sub>	Data Hold Time		1			μs
t <sub>DF</sub>	Output Enable to Output Float Delay	CE/PGM = X	0		60	ns
t <sub>PW</sub>	Program Pulse Width		45	50	105	μs
t <sub>OE</sub>	Data Valid from OE	CE/PGM = X			100	ns
I <sub>PP</sub>	V <sub>PP</sub> Supply Current during Programming Pulse	CE/PGM = V <sub>IL</sub>			30	mA
I <sub>cc</sub>	V <sub>CC</sub> Supply Current				30	mA
T <sub>A</sub>	Temperature Ambient		20	25	30	°C
V <sub>cc</sub>	Power Supply Voltage		6.25	6.5	6.75	V
V <sub>PP</sub>	Programming Supply Voltage		12.5	12.75	13.0	V
t <sub>FR</sub>	Input Rise, Fall Time		5			ns
V <sub>IL</sub>	Input Low Voltage		-0.1	0.0	0.45	V
V <sub>IH</sub>	Input High Voltage		2.4	4.0		V
t <sub>IN</sub>	Input Timing Reference Voltage		0.8		2.0	V
t <sub>OUT</sub>	Output Timing Reference Voltage		0.8		2.0	V

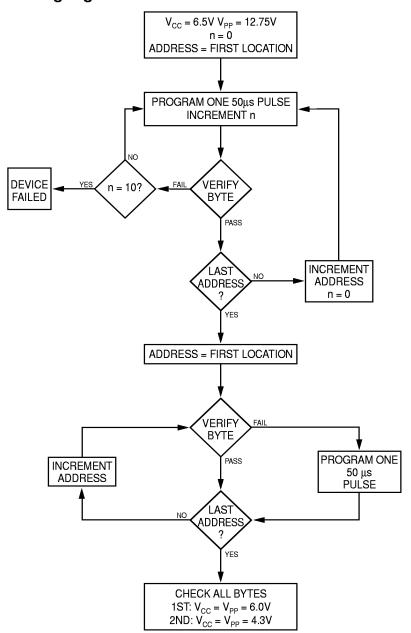
Note 10: Fairchild's standard product warranty applies only to devices programmed to specifications described herein.

Note 11:  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ . The EPROM must not be inserted into or removed from a board with voltage applied to  $V_{PP}$  or  $V_{CC}$ .

Note 12: The maximum absolute allowable voltage which may be applied to the V<sub>PP</sub> pin during programming is 14V. Care must be taken when switching the V<sub>PP</sub> supply to prevent any overshoot from exceeding this 14V maximum specification. At least a 0.1 µF capacitor is required across V<sub>PP</sub>, V<sub>CC</sub> to GND to suppress spurious voltage transients which may damage the device.

Note 13: During power up the  $\overline{\text{CE}/\text{PGM}}$  pin must be brought high ( $\geq V_{\text{IH}}$ ) either coincident with or before power is applied to  $V_{\text{PP}}$ .

# **Turbo Programming Algorithm Flow Chart**



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Note: The standard National Semiconductor Fast Programming Algorithm may also be used.

### FIGURE 1.

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# Functional Description DEVICE OPERATION

The six modes of operation of the EPROM are listed in Table 1. It should be noted that all inputs for the six modes are at TTL levels. The power supplies required are  $V_{\rm CC}$  and  $V_{\rm PP}$ . The  $V_{\rm PP}$  power supply must be at 12.75V during the three programming modes, and must be at 5V in the other three modes. The  $V_{\rm CC}$  power supply must be at 6.25V during the three programming modes, and at 5V in the other three modes.

### **Read Mode**

The EPROM has two control functions, both of which must be logically active in order to obtain data at the outputs. Chip Enable  $(\overline{\text{CE/PGM}})$  is the power control and should be used for device selection. Output Enable  $(\overline{\text{OE}})$  is the output control and should be used to gate data to the output pins, independent of device selection. Assuming that addresses are stable, address access time  $(t_{\text{ACC}})$  is equal to the delay from  $\overline{\text{CE}}$  to output  $(t_{\text{CE}})$ . Data is available at the outputs  $t\overline{\text{OE}}$  after the falling edge of  $\overline{\text{OE}}$ , assuming that  $\overline{\text{CE/PGM}}$  has been low and addresses have been stable for at least  $t_{\text{ACC}}$ - $t_{\text{OE}}$ .

### Standby Mode

The EPROM has a standby mode which reduces the active power dissipation by over 99%, from of 65 mW to 0.55 mW. The EPROM is placed in the standby mode by applying a CMOS high signal to the CE/PGM input. When in standby mode, the outputs are in a high impedance state, independent of the OE input.

# **Output Disable**

The EPROM is placed in output disable by applying a TTL high signal to the  $\overline{OE}$  input. When in output disable all circuitry is enabled, except the outputs are in a high impedance state (TRI-STATE).

### **Output OR-Typing**

Because the EPROM is usually used in larger memory arrays, Fairchild has provided a 2-line control function that accommodates this use of multiple memory connections. The 2-line control function allows for:

- 1. the lowest possible memory power dissipation, and
- 2. complete assurance that output bus contention will not occur.

To most efficiently use these two control lines, it is recommended that  $\overline{CE/PGM}$  be decoded and used as the primary device selecting function, while  $\overline{OE}$  be made a common connection to all devices in the array and connected to the READ line from the system control bus. This assures that all deselected memory devices are in their low power standby modes and that the output pins are active only when data is desired from a particular memory device.

### **Programming**

CAUTION: Exceeding 14V on pin 1 (V<sub>PP</sub>) will damage the EPROM.

Initially, and after each erasure, all bits of the EPROM are in the "1's" state. Data is introduced by selectively programming "0's" into the desired bit locations. Although only "0's" will be programmed, both "1's" and "0's" can be presented in the data word..

The EPROM is in the programming mode when the  $V_{PP}$  power supply is at 12.75V and  $\overline{OE}$  is at  $V_{IH}$ . It is required that at least a

 $0.1\,\mu\text{F}$  capacitor be placed across  $V_{PP},\,V_{CC}$  to ground to suppress spurious voltage transients which may damage the device. The data to be programmed is applied 8 bits in parallel to the data output pins. The levels required for the address and data inputs are TTL.

When the address and data are stable, an active low, TTL program pulse is applied to the  $\overline{\text{CE/PGM}}$  input. A program pulse must be applied at each address location to be programmed. The EPROM is programmed with the Turbo Programming Algorithm shown in Figure 1. Each Address is programmed with a series of 50  $\mu$ s pulses until it verifies good, up to a maximum of 10 pulses. Most memory cells will program with a single 50  $\mu$ s pulse. (The standard National Semiconductor Algorithm may also be used but it will have longer programming time.)

The  $\overline{\text{EPROM}}$  must not be programmed with a DC signal applied to the  $\overline{\text{CE/PGM}}$  input.

Programming multiple EPROM in parallel with the same data can be easily accomplished due to the simplicity of the pro-gramming requirements. Like inputs of the parallel EPROM may be connected together when they are programmed with the same data. A low level TTL pulse applied to the CE/PGM input programs the paralleled EPROM.

### **Program Inhibit**

Programming multiple EPROMs in parallel with different data is also easily accomplished. Except for CE/PGM all like in-puts (including OE) of the parallel EPROMs may be com-mon. A TTL low level program pulse applied to an EPROM's CE/PGM input with V<sub>PP</sub> at 12.75V will program that EPROM. A TTL high level CE/PGM input inhibits the other EPROMs from being programmed.

### **Program Verify**

A verify should be performed on the programmed bits to determine whether they were correctly programmed. The verify may be performed with  $V_{PP}$  at 12.75V.  $V_{PP}$  must be at  $V_{CC}$ , except during programming and program verify.

## **MANUFACTURER'S IDENTIFICATION CODE**

The EPROM has a manufacturer's identification code to aid in programming. When the device is inserted in an EPROM programmer socket, the programmer reads the code and then automatically calls up the specific programming algorithm for the part. This automatic programming control is only possible with programmers which have the capability of reading the code.

The Manufacturer's Identification code, shown in Table 2, specifically identifies the manufacturer and device type. The code for FM27C040 is "8F08", where "8F" designates that it is made by Fairchild Semiconductor, and "08" designates a 4 Megabit (512K  $\times$  8) part.

The code is accessed by applying 12V  $\pm 0.5V$  to address pin A9. Addresses A1–A8, A10–A18, and all control pins are held at  $V_{\parallel L}$  Address pin A0 is held at  $V_{\parallel L}$  for the manufacturer's code, and held at  $V_{\parallel H}$  for the device code. The code is read on the eight data pins, O0 –O7 . Proper code access is only guaranteed at  $25^{\circ}C$   $\pm$   $5^{\circ}C$ .

# Functional Description (Continued) SYSTEM CONSIDERATION

The power switching characteristics of EPROMs require careful decoupling of the devices. The supply current,  $I_{\rm CC}$ , has three segments that are of interest to the system designer: the standby current level, the active current level, and the transient current peaks that are produced by voltage transitions on input pins. The magnitude of these transient current peaks is dependent of the output capacitance loading of the device. The associated  $V_{\rm CC}$  transient voltage peaks can be suppressed by properly selected

decoupling capacitors. It is recommended that at least a 0.1  $\mu F$  ceramic capacitor be used on every device between  $V_{CC}$  and GND. This should be a high frequency capacitor of low inherent inductance. In addition, at least a 4.7  $\mu F$  bulk electrolytic capacitor should be used between  $V_{CC}$  and GND for each eight devices. The bulk capacitor should be located near where the power supply is connected to the array. The purpose of the bulk capacitor is to overcome the voltage drop caused by the inductive effects of the PC board traces.

### **Mode Selection**

The modes of operation of the FM27C040 are listed in Table 1. A single 5V power supply is required in the read mode. All inputs are TTL levels except for  $V_{pp}$  and A9 for device signature.

**TABLE 1. Modes Selection** 

Pins Mode	CE/PGM	OE	V <sub>PP</sub>	V <sub>cc</sub>	Outputs
Read	V <sub>IL</sub>	V <sub>IL</sub>	X (Note 15)	5.0V	D <sub>OUT</sub>
Output Disable	X	V <sub>IH</sub>	X	5.0V	High Z
Standby	V <sub>IH</sub>	X	X	5.0V	High Z
Programming	V <sub>IL</sub>	V <sub>IH</sub>	12.75V	6.25V	D <sub>IN</sub>
Program Verify	X	V <sub>IL</sub>	12.75V	6.25V	D <sub>OUT</sub>
Program Inhibit	V <sub>IH</sub>	V <sub>IH</sub>	12.75V	6.25V	High Z

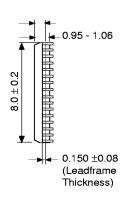
Note 15: X can be  $V_{IL}$  or  $V_{IH}$ 

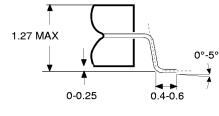
### TABLE 2. Manufacturer's Identification Code

Pins	A0 (12)	A9 (26)	O7 (21)	O6 (20)	O5 (19)	O4 (18)	O3 (17)	O2 (15)	O1 (14)	O0 (13)	Hex Data
Manufacturer Code	V <sub>IL</sub>	12V	1	0	0	0	1	1	1	1	8F
Device Code	V <sub>IH</sub>	12V	0	0	0	0	1	0	0	0	08

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# Physical Dimensions inches (millimeters) unless otherwise noted 20.0 ± 0.2 10.5 Typ 10.15-0.25 TYP

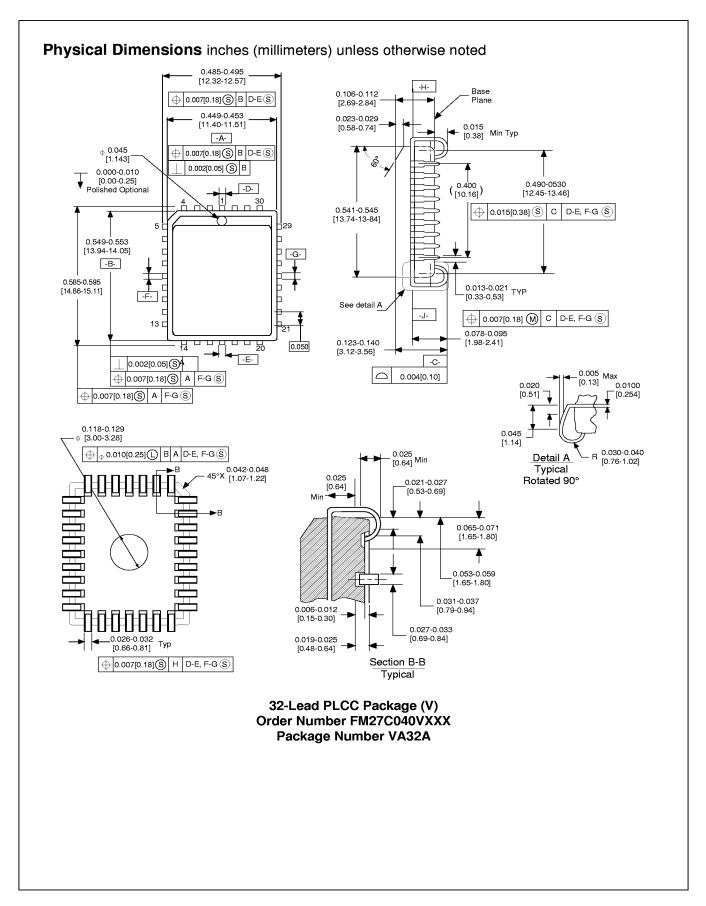




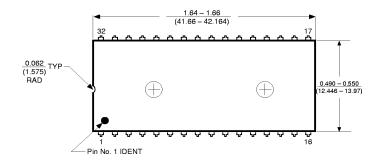
DETAIL A Typical

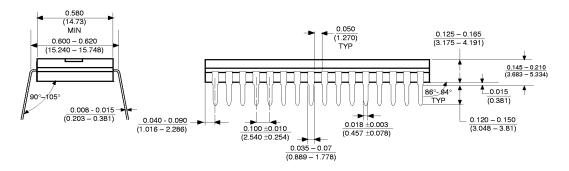
32-Lead TSOP Package (T) Order Number FM27C040TXXX Package Number MBH32A

See Detail A



# Physical Dimensions inches (millimeters) unless otherwise noted





32-Lead PDIP Package
Order Number FM27C040NXXX

# **Life Support Policy**

Fairchild's products are not authorized for use as critical components in life support devices or systems without the express written approval of the President of Fairchild Semiconductor Corporation. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform, when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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